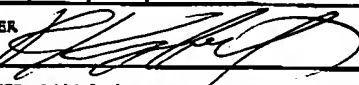


Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M22-2379		SERIAL NO. 10632,273	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Warren M. Farnsworth et al.			
				FILING DATE July 31, 2003		GROUP 2859 2859	
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Examiner Initial	Class	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
PK	AA	10632,273 5580821	12/03/96	Ataxmine	216	2	
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AM						
	AN						
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Page(s), Etc.)							
	AR						
	AS						
	AT						
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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Warren M. Farnworth et al.		
					FILING DATE Filed Herewith	GROUP N/A 2829	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>RK</i>	AA	3,412,456	11/68	Ebisawa			
<i>RK</i>	AB	3,469,019	9/69	Reinmann			
<i>RK</i>	AC	4,105,970	8/78	Katz			
<i>RK</i>	AD	4,141,055	2/79	Berry et al.			
<i>RK</i>	AE	4,182,781	1/80	Hooper et al.			
<i>RK</i>	AF	4,189,825	2/80	Robillard et al.			
<i>RK</i>	AG	4,312,117	1/82	Robillard et al.			
<i>RK</i>	AH	4,315,984	2/82	Okazaki et al.			
<i>RK</i>	AI	4,417,206	11/83	Stowers			
<i>RK</i>	AJ	4,499,656	2/85	Fabian et al.			
<i>RK</i>	AK	4,585,991	4/86	Reid et al.			
<i>RK</i>	AL	4,881,118	11/89	Niwayama et al.			
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
<i>RK</i>	AM	53171	03/91	Japan			
<i>RK</i>	AN	108350	05/91	Japan			
<i>RK</i>	AO	329314	08/89	European (EPO)			
<i>RK</i>	AP	6744030 57143838	09/82	Japan			
<i>RK</i>	AQ	2-5540	01/90	Japan			
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
<i>RK</i>	AR	Moto's Nakano "A Probe for Testing Semiconductor Integrated Circuits and a Test Method Using Said Probe." 25 March, 1991					
		Japanese Patent Office Disclosure No. Hei 3-69131, Filing No. Hei 1-205301, Filing Date August 8, 1989					
	AS						
	AT						
EXAMINER <i>RK</i>				DATE CONSIDERED 8-24-04			
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U.S. PATENT DOCUMENTS								
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
<i>RL</i>	AU	4,924,589	Leedy					
<i>RL</i>	AV	4,929,999	Hoebrechts et al.					
<i>RL</i>	AW	4,937,653	Blonder et al.					
<i>RL</i>	AX	4,952,272	Okino et al.					
<i>RL</i>	AY	4,963,225	Lehman-Lemar					
<i>RL</i>	AZ	5,420,520	Anschel et al.					
<i>RL</i>	BA	5,014,161	Lee et al.					
<i>RL</i>	BB	5,032,541	Sakamoto et al.					
<i>RL</i>	BC	5,045,780	Swart					
<i>RL</i>	BD	5,072,116	Kawade et al.					
<i>RL</i>	BE	5,103,557	Leedy					
<i>RL</i>	BF	5,137,461	Bindra et al.					
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
<i>RL</i>	BG	2232946	09/90	Japan				
<i>RL</i>	BH	410446	01/92	Japan				
	BI							
	BJ							
	BK							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	BL							
	BM							
	BN							
EXAMINER <i>R. J. [Signature]</i>				DATE CONSIDERED 8-24-04				
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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Warren M. Farnworth et al.			
					FILING DATE Filed Herewith		GROUP N/A 2829	
U.S. PATENT DOCUMENTS								
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
<i>RL</i>	BO	5,177,438	1/93	Littlebury et al.	7	7		
<i>RL</i>	BP	5,177,439	1/93	Liu et al.				
<i>RL</i>	BQ	5,196,251	3/93	Bakhru et al.				
<i>RL</i>	BR	5,206,585	4/93	Chang et al.				
<i>RL</i>	BS	5,235,140	8/93	Reele et al.				
<i>RL</i>	BT	5,239,260	8/93	Widder et al.				
<i>RL</i>	BU	5,245,135	9/93	Schreiber et al.				
<i>RL</i>	BV	5,262,718	11/93	Svendsen et al.				
<i>RL</i>	BW	5,307,561	5/94	Feigenbaum et al.				
<i>RL</i>	BX	5,323,035	6/97	Leedy				
<i>RL</i>	BY	5,326,428	7/94	Farnworth et al.				
<i>RL</i>	BZ	5,334,804	8/94	Love et al.				
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	CA							
	CB							
	CC							
	CD							
	CE							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	CF							
	CG							
	CH							
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				FILING DATE Filed Herewith	GROUP N/A 2829			
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>RL</i>	CI	5,353,195	10/94	Fillion et al.				
<i>RL</i>	CJ	5,367,253	11/94	Wood et al.				
<i>RL</i>	CK	5,402,077	03/95	Agabdel et al.				
<i>RL</i>	CL	5,419,807	05/95	Akram et al.				
<i>RL</i>	CM	5,431,328	07/95	Chang et al.				
<i>RL</i>	CN	5,478,779	12/95	Akram				
<i>RL</i>	CO	5,468,917	11/95	Brodsky et al.				
<i>RL</i>	CP	5,471,151	11/95	DiFrancesco				
<i>RL</i>	CQ	5,477,087	12/95	Kwakita et al.				
<i>RL</i>	CR	5,523,697	06/96	Farnworth et al.				
<i>RL</i>	CS	5,541,525	07/96	Wood et al.				
<i>RL</i>	CT	5,559,444	09/93	Farnworth et al.				
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	CU							
	CV							
	CW							
	CX							
	CY							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	CZ							
	DA							
	DB							
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U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>RK</i>	DC	5,625,297	04/97	Amaudov et al.				
<i>RK</i>	DD	5,716,218	02/98	Farnworth et al.				
<i>RK</i>	DE	5,790,337	08/98	Schreiber et al.				
<i>RK</i>	DF	5,831,832	11/98	Gillette et al.				
<i>RK</i>	DG	5,849,633	12/98	Akram				
<i>RK</i>	DH	5,869,787	02/99	Akram				
<i>RK</i>	DI	6,002,266	12/99	Briggs et al.				
<i>RK</i>	DJ	6,093,643	07/00	Akram				
<i>RK</i>	DK	4,566,184	01/86	Higgins et al.				
<i>RK</i>	DL	5,838,160	11/17/1998	Beaman et al.				
<i>RK</i>	DM	4,571,540	2/18/1986	Stowers et al.				
<i>RK</i>	DN	4,116,523	09/26/78	Coberly et al.				
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	DO							
	DP							
	DQ							
	DR							
	DS							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	DT							
	DU							
	DV							
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